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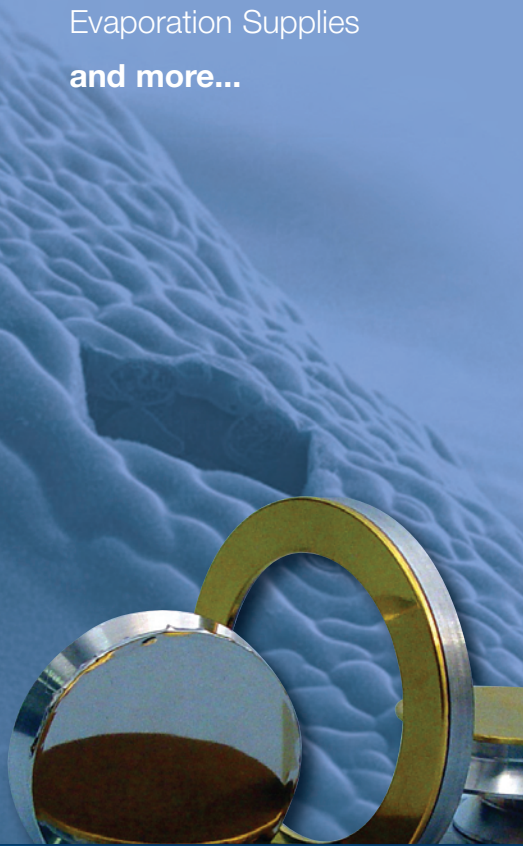
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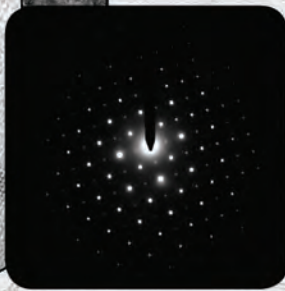
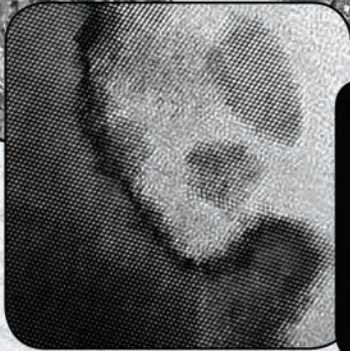
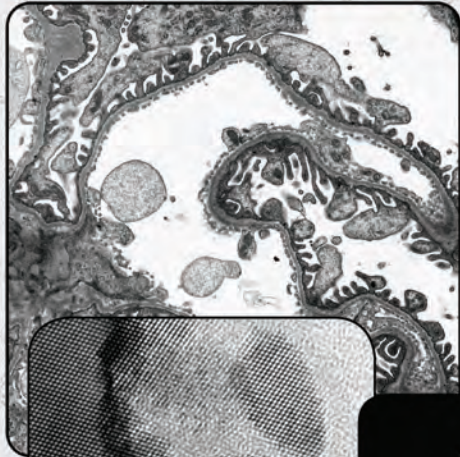
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ANALYSIS OF CULTURAL HERITAGE SPECIAL SECTION

Introduction: Analysis of Cultural Heritage 655
Clive Walker and Ineke Joosten

A SEM-EDS Study of Cultural Heritage Objects with Interpretation of Constituents and Their Distribution Using PARC Data Analysis 656
Corrie J.G. van Hoek, Michiel de Roo, Grishja van der Veer, and Sieger R. van der Laan

The External Ion Microbeam of the LABEC Laboratory in Florence: Some Applications to Cultural Heritage 661
Silvia Calusi

Portable Apparatus for *In Situ* X-Ray Diffraction and Fluorescence Analyses of Artworks 667
Myriam Eveno, Brice Moignard, and Jacques Castaing

PXRF, μ -XRF, Vacuum μ -XRF, and EPMA Analysis of *Email Champlevé* Objects Present in Belgian Museums 674
Veerle Van der Linden, Eva Meesdom, Annemie Devos, Rita Van Dooren, Hans Nieuwdorp, Elsje Janssen, Sophie Balace, Bart Vekemans, Laszlo Vincze, and Koen Janssens

Quantitative Determination of van Gogh's Painting Grounds Using SEM/EDX 686
Ralph Haswell, Leslie Carlyle, and Kees T.J. Mensch

Multispectral Infrared Reflectography to Differentiate Features in Paintings 691
Claudia Daffara and Raffaella Fontana

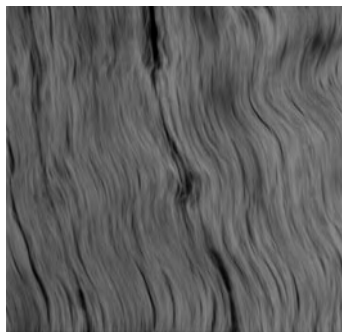
SEM Backscattered-Electron Images of Paint Cross Sections as Information Source for the Presence of the Lead White Pigment and Lead-Related Degradation and Migration Phenomena in Oil Paintings 696
Katrien Keune, Annelies van Loon, and Jaap J. Boon

MICROANALYSIS APPLICATIONS

Study of Mural Paintings Using *In Situ* XRF, Confocal Synchrotron- μ -XRF, μ -XRD, Optical Microscopy, and SEM-EDS—The Case of the Frescoes from Misericordia Church of Odemira 702
S. Valadas, A. Candeias, J. Mirão, D. Tavares, J. Coroado, Rolf Simon, A.S. Silva, M. Gil, A. Guilherme, and M.L. Carvalho

Quantitative Energy Dispersive X-Ray Analysis of Submicrometric Particles Using a Scanning Electron Microscope 710
Luigi Paoletti, Biagio M. Bruni, Antonio Gianfagna, Simona Mazzotti-Tagliani, and Alessandro Pacella

An Examination of Kernite ($\text{Na}_2\text{B}_4\text{O}_6(\text{OH})_2 \cdot 3\text{H}_2\text{O}$) Using X-Ray and Electron Spectroscopies: Quantitative Microanalysis of a Hydrated Low-Z Mineral 718
Douglas C. Meier, Jeffrey M. Davis, and Edward P. Vicenzi



On the Cover: Multiphoton laser scanning microscopy image showing collagen organization in the medical collateral ligament of a rat. For further information see Chamberlain et al., pages 779–787.

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MATERIALS APPLICATIONS

- Comprehensive Comparison of Various Techniques for the Analysis of Elemental Distributions in Thin Films 728
D. Abou-Ras, R. Caballero, C.-H. Fischer, C. Kaufmann, I. Lauer mann, R. Mainz, H. Mönig, A. Schöpke, C. Stephan, C. Streeck, S. Schorr, A. Eicke, M. Döbeli, B. Gade, J. Hinrichs, T. Nunnay, H. Dijkstra, V. Hoffmann, D. Klemm, V. Efimova, A. Bergmaier, G. Dollinger, T. Wirth, W. Unger, A.A. Rockett, A. Perez-Rodriguez, J. Alvarez-Garcia, V. Izquierdo-Roca, T. Schmid, P.-P. Choi, M. Müller, F. Bertram, J. Christen, H. Khatri, R.W. Collins, S. Marsillac, and I. Kötschau
- Electron Image Series Reconstruction of Twin Interfaces in InP Superlattice Nanowires 752
Martin Ek, Magnus T. Borgström, Lisa S. Karlsson, Crispin J.D. Hetherington, and L. Reine Wallenberg
- Structure and Chemistry across Interfaces at Nanoscale of a Ge Quantum Well Embedded within Rare Earth Oxide Layers 759
Tanmay Das and Somnath Bhattacharyya
- Influence of Surfactant Concentration on the Surface Morphology of Hollow Silica Microspheres and Its Explanation 766
Shiquan Liu, Meiyang Wei, Pegie Cool, Cynthia Van Oers, and Jiancun Rao
- Closed-Cell Foam Skin Thickness Measurement Using a Scanning Electron Microscope 772
Clifford S. Todd and Valentina Kuznetsova

BIOLOGICAL APPLICATIONS

- Quantification of Collagen Organization and Extracellular Matrix Factors within the Healing Ligament 779
Connie S. Chamberlain, Erin M. Crowley, Hirohito Kobayashi, Kevin W. Eliceiri, and Ray Vanderby
- Minerals and Aligned Collagen Fibrils in Tilapia Fish Scales: Structural Analysis Using Dark-Field and Energy-Filtered Transmission Electron Microscopy and Electron Tomography 788
Mitsuhiro Okuda, Nobuhiro Ogawa, Masaki Takeguchi, Ayako Hashimoto, Motohiro Tagaya, Song Chen, Nobutaka Hanagata, and Toshiyuki Ikoma
- A Novel Algorithm for the Determination of Bacterial Cell Volumes That is Unbiased by Cell Morphology 799
M. Zeder, E. Kohler, L. Zeder, and J. Pernthaler

EQUIPMENT/TECHNIQUES DEVELOPMENT

- Application of Colloidal Palladium Nanoparticles for Labeling in Electron Microscopy 810
Marie Vancová, Miroslav Šlouf, Jan Langhans, Eva Pavlová, and Jana Nebesářová
- The Three-Dimensional Point Spread Function of Aberration-Corrected Scanning Transmission Electron Microscopy 817
Andrew R. Lupini and Niels de Jonge
- A Piezoelectric Goniometer Inside a Transmission Electron Microscope Goniometer 827
Wei Guan, Aiden Lockwood, Beverly J. Inkson, and Günter Möbus
- High Contrast Magnetic and Nonmagnetic Sample Current Microscopy for Bulk and Transparent Samples Using Soft X-Rays 834
Daniela Nolle, Markus Weigand, Gisela Schütz, and Eberhard Goering

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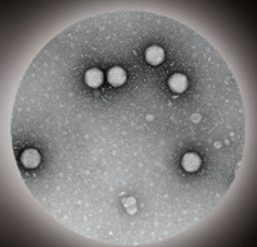
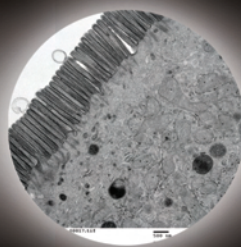
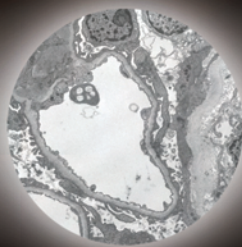
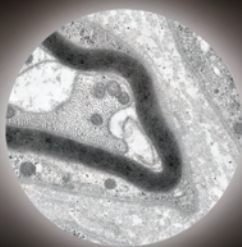
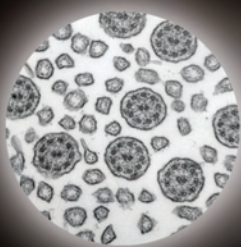
- The Image Processing Handbook* by John C. Russ 843
Lou Ross

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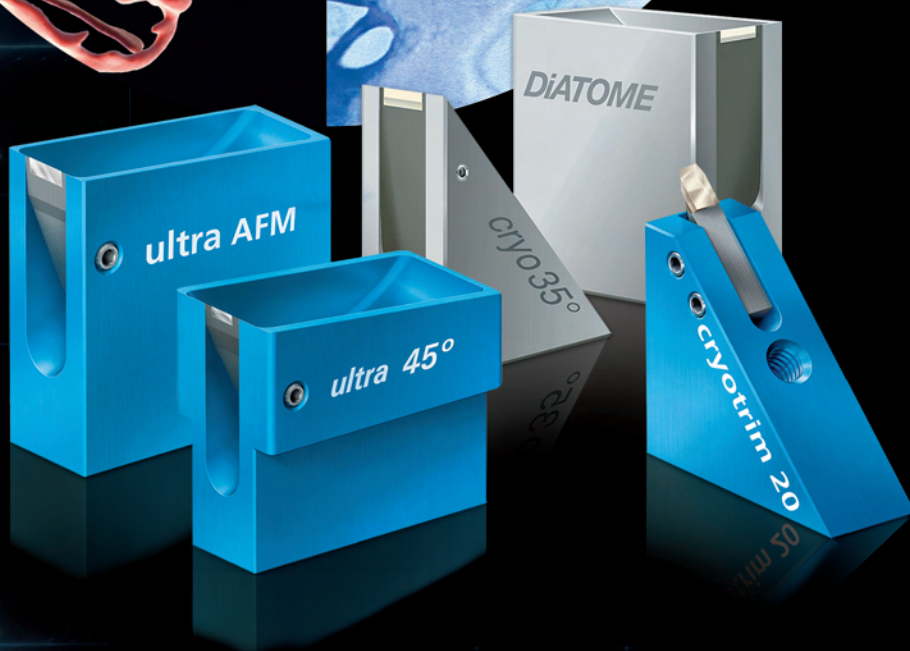
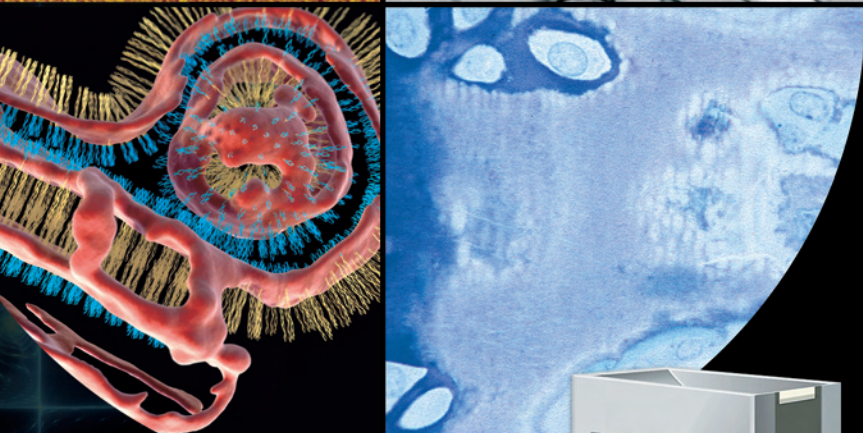
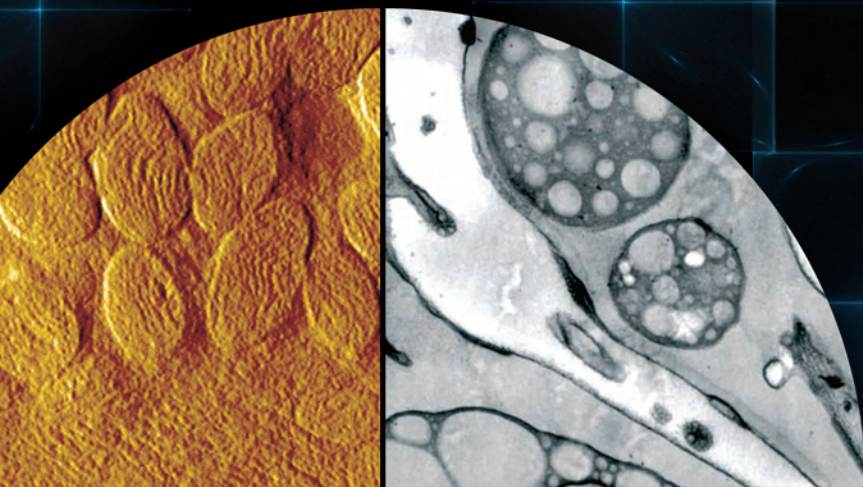
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FIGs are only open to current MSA members. For an additional fee of \$10.00, Each FIG provides periodic information on a specific area of interest. And most groups expand on this information through live discussion at the *Microscopy & Microanalysis Annual Meeting* each summer. Approximately nine Focused Interest Groups currently exist and more are constantly in development.

Most MSA members join one or more FIGs online through the normal membership renewal process, but membership is available anytime throughout the year. Visit the MSA web site for a list of current Focused Interest Groups and their primary contacts.

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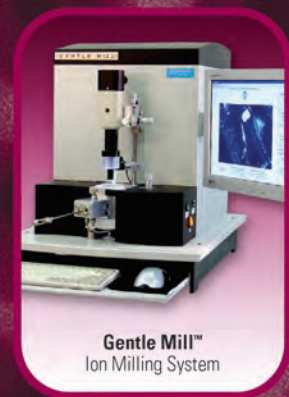
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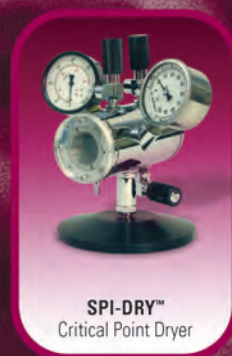
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